

# A Non-volatile Memory Platform

# You've Never Seen

**Project Leader Engineer** 

Kevin Liao

<u> 精彩回顧:https://youtu.be/V2FDaxBDYWg</u>







### **NVM Platform Application**

### **♦ NVM Platform Function**

### **♦** Summary



# **NVM Platform Application**



### **NVM Platform Can Support Different NVMs**



Sources : Association Française des Diabétiques et Fédération Française des Diabétiques

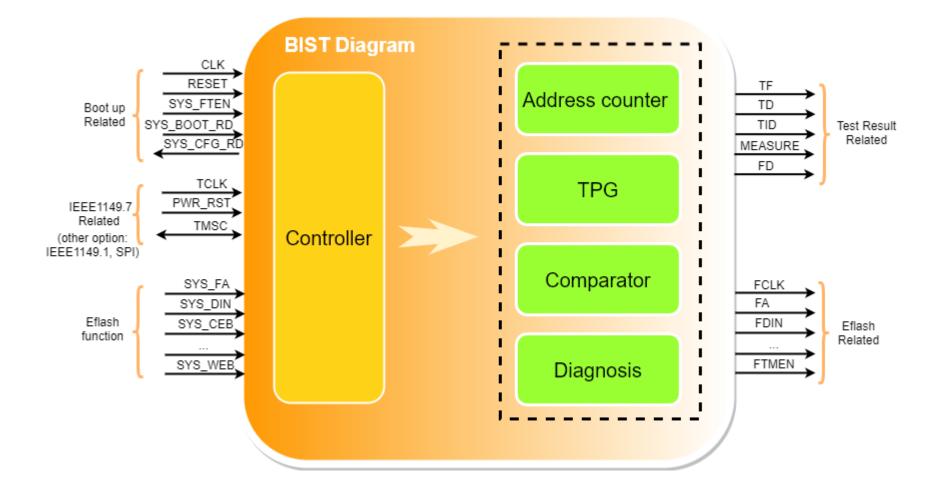
source:tsmc



# **NVM Platform Function**



### **NVM Platform - BIST Diagram**



### **NVM Platform - Support Foundry**

### ◆eFlash series

### **MTP** series

**♦ MRAM**, **RRAM** series



### **NVM Platform - Generate Different Clock**

According to the various clock frequencies on the chip design, NVM Platform can generate the time parameters in a short time. Engineers can get various optimized parameters according to the condition of various status anytime.



### **NVM Platform - Support Different Test Items**

- Fully customized test items
- Part of the test items (Options)
- Flash test algorithm (March FT)

March FT	GPD	GED	DPD	DED	OE	RD
	100%	100%	100%	100%	100%	100%
	SAF	TF	SOF	AF	CFst	
	100%	100%	100%	100%	100%	

### **NVM Platform - Support Different Communication Interfaces**

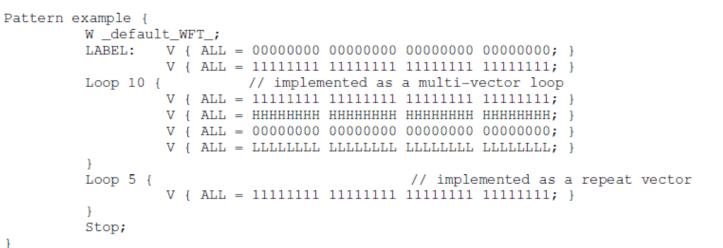
### **♦ Users can choose one of the following three methods:**

- IEEE1149.1 interface (5 ports)
- IEEE1149.7 interface (3 ports)
- SPI interface

### **NVM Platform - Support Different Pattern Vector** Format

### **STIL vector**

```
Example
```



### **◆TEXT vector (For different ATE )**

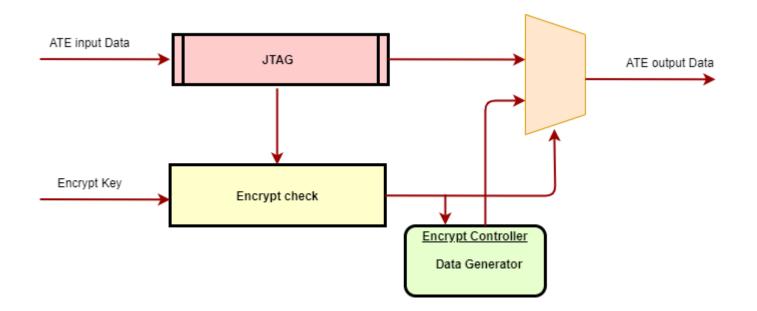
■ Example : CHROMA, J750 , V93K... etc



### **NVM Platform - Security Protect**

- Security and testability are the important factors affecting designing for testability.
- Support a secure method to protect data of the JTAG interface. The encrypt key has 128 bits.

### **NVM Platform - Security Diagram**











# The Platform NVM IP of IoT Applications

#### The technology improvement

• With faster wireless networks, superior sensors and revolution computing capabilities, the IoT improves the current devices in power, precision, and availability. It has been growing huge business opportunities.

#### The Platform NVM IP of IoT cases

- Wearables
- Smart Home Applications
- Health care
- Smart Cities
- Agriculture
- Industrial Automation



# What iSTART Platform Offers (1)

#### Customized design

 Provide a customized design BIST/BISR IP functions, which can be matched with different NVM sizes to generate corresponding test/repair IP

#### Experience

• Many SST/ISSI eFlash BIST/BISR IP mass production experience

#### Flexible

 Flexible interface configuration (5 ports IEEE1149.1 , 3 ports IEEE 1149.7 , SPI mode , customize design)



# What iSTART Platform Offers (2)

#### **Repair function**

 Repair function improves the yield, and can be matched with power-on or dynamic test functions to meet the high reliability requirements of automotive and industrial grades

#### Easily achieve

 Customer can easily achieve a balance between test coverage and testing cost time in flexible enabled and disabled test items.

#### Flexible

• Perform flexible user command test actions

# What iSTART Platform Offers (3)

#### Diagnostic

 Provide diagnostic information to determine the type and location of the error for test time optimization

#### Area

 Optimize the BIST/BISR area according to customer needs and support programming trimming data

#### Security

• Customized security design to protect the customer data safety

## **iSTART eFlash BIST/BISR IP Advantages**

SiliconeFlash BIST and BISR IP repeated orders,Proventhe only eFlash BIST and BISR IP partner

110nm, 55nm, 40nm silicon verification experience

BIST and BISR IP shipped to Japanese automotive IC manufacturers

### **Tool Platform advantages**

#### Automation

- Directly generate corresponding BIST/BISR IP for different NVM size in GUI tool platform based
- Simple platform, good reusability, greatly reducing NVM BIST design coding time
- Testbench directly generates the corresponding ATE test vector STIL/Text format

#### Flexible

- Support NVM Scramble test design
- Output BIST design is Soft IP, easily integrate into SoC design

#### **Diagnosis function**

 Customer feedback test time is shortened to 1/5 of original test time, greatly reducing test cost





♀ 芯測科技

Ļ